

Spatio-temporal imaging of strain and structure in devices and nanostructures by X-ray nano diffraction imaging methods

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Amphithéâtre SOLEIL

Spatially resolving X-ray diffraction based tools are of relevance for the characterization of most emerging nanomaterials or electronic devices. While typical samples for these techniques are microelectronic structures, the resolving power has proven to reach down to length scales relevant for catalysis and basic solid state chemistry as encountered in most electrochemical systems. Beamline ID01 is specialized on the imaging of strain and structure under Bragg diffraction conditions. Most recent efforts show that high resolution in reciprocal and real space is now obtained on time scales allowing to follow operando in areas and on timescales ranging from Batteries (seconds to hours) down to sub nanosecond time resolved imaging of functioning electronic devices.



Pause café

SEMINAIRE

Formalités d'entrée : accès libre dans l'amphi du pavillon d'Accueil.
Si la manifestation a lieu dans le Grand Amphi SOLEIL du Bâtiment Central merci de vous munir d'une pièce d'identité (à échanger à l'accueil contre un badge d'accès).

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